

# Search Notes



Application/Control No.

10/665,920

Examiner

Hiep Nguyen

Applicant(s)/Patent under Reexamination

MILLER, EDWARD E.

Art Unit

2816

## SEARCHED

Class	Subclass	Date	Examiner
327	205	01.28.05	NA
	77	T	T
	537		
	407		
	408		
	63		
	65		
	66		
Updated Standing		07.07.05	NA
327	205	—	—

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST	01.28.05	NA
EAST	07.05.05	NA